

# UNISONIC TECHNOLOGIES CO., LTD

UF9540 Preliminary Power MOSFET

# -100V, -23A P-CHANNEL POWER MOSFET

#### ■ DESCRIPTION

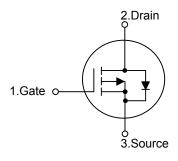
The UTC **UF9540** is an P-channel power MOSFET using UTC's utilize advanced processing techniques to achieve extremely low on-resistance per silicon area.

This benefit, combined with the fast switching speed and ruggedized device design Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

#### ■ FEATURES

- \* Advanced Process Technology
- \* Dynamic dv/dt Rating
- \* Fast Switching
- \* Fully Avalanche Rated

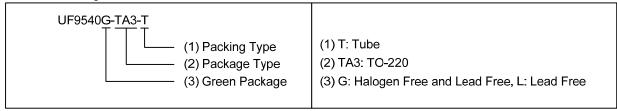
#### ■ SYMBOL



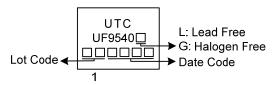
#### ORDERING INFORMATION

Ordering Number		Dardina	Pin Assignment			Daalina	
Lead Free	Halogen Free	Package	1	2	3	Packing	
UF9540L-TA3-R	UF9540G-TA3-T	TO-220	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



#### MARKING



TO-220

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# ■ ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub>=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		$V_{ extsf{DSS}}$	-100	V
Gate to Source Voltage		$V_{GSS}$	±20	V
Drain Current	Continuous	I <sub>D</sub>	-23	Α
	Pulsed (Note 2)	$I_{DM}$	-64	Α
Avalanche Energy	Single Pulsed (Note 3)	E <sub>AS</sub>	62	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	3.7	V/ns
Power Dissipation		$P_D$	65	W
Junction Temperature		TJ	+150	°C
Storage Temperature		$T_{STG}$	-55 ~ +150	°C

- Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
  - 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
  - 3. L = 0.1mH,  $I_{AS}$  = -35.4A,  $V_{DD}$  = -50V,  $R_G$  = 25 $\Omega$ , Starting  $T_J$ =25 $^{\circ}C$
  - 4.  $I_{SD} \le$  -23A, di/dt  $\le$  200A/ $\mu$ s,  $V_{DD} \le$  BV $_{DSS}$ , Starting  $T_J$ =25°C

### ■ THERMAL DATA

PARAMETER	SYMBOL	PATINGS	UNIT	
Junction-to-Ambient	$\theta_{JA}$	62.5	°C/W	
Junction-to-Case	$\theta_{JC}$	1.92	°C/W	

### ■ ELECTRICAL CHARACTERISTICS (T<sub>J</sub>=25°C, unless otherwise specified)

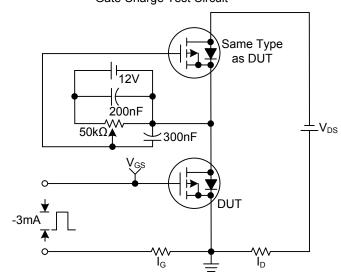
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		$V_{(BR)DSS}$	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA	-100			V
Drain-Source Leakage Current		I <sub>DSS</sub>	V <sub>DS</sub> =-100V, V <sub>GS</sub> =0V			-100	μA
Gate-Source Leakage Current	Forward		V <sub>GS</sub> =+20V			+100	nA
	Reverse	I <sub>GSS</sub>	V <sub>GS</sub> =-20V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$ , $I_{D}=-250\mu A$	-2.0		-4.0	V
Drain-Source On-State Resistance		R <sub>DS(ON)</sub>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-6.6A			110	mΩ
DYNAMIC PARAMETERS							
Input Capacitance	nput Capacitance				2520		pF
Output Capacitance		Coss	$V_{DS}$ =-25V, $V_{GS}$ =0V, f=1.0MHz		135		pF
Reverse Transfer Capacitance		$C_{RSS}$			105		pF
SWITCHING PARAMETERS							
Total Gate Charge		$Q_{G}$	\( - 90\\ \\ - 40\\ \  - 22A		41		nC
Gate-Source Charge		$Q_GS$	V <sub>DS</sub> =-80V, V <sub>GS</sub> =-10V, I <sub>D</sub> =-23A (Note 1, 2)		11.5		nC
Gate-Drain Charge		$Q_GD$	(Note 1, 2)		11		nC
Turn-ON Delay Time		t <sub>D(ON)</sub>			12		ns
Turn-ON Rise Time		$t_R$	V <sub>DD</sub> =-50V, V <sub>GS</sub> =-10V,		18		ns
Turn-OFF Delay Time		t <sub>D(OFF)</sub>	$I_D$ =-23A, $R_G$ =3 $\Omega$ (Note 1, 2)		33		ns
Turn-OFF Fall Time		t <sub>F</sub>			20		ns
SOURCE- DRAIN DIODE RATI	NGS AND (	CHARACTERI	STICS				
Maximum Body-Diode Continuous Current		Is				-23	Α
Maximum Body-Diode Pulsed Current		I <sub>SM</sub>				-64	Α
Drain-Source Diode Forward Voltage		$V_{SD}$	I <sub>S</sub> =-23A, V <sub>GS</sub> =0V			-1.4	V
Body Diode Reverse Recovery Time		t <sub>rr</sub>	I <sub>F</sub> =-23A,		51		ns
Body Diode Reverse Recovery Charge		$Q_{rr}$	dI/dt=100A/µs (Note 4)		90		nC

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

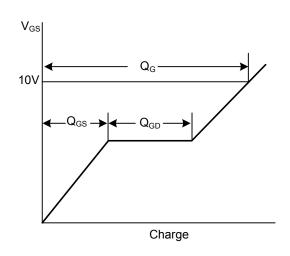
2. Essentially independent of operating temperature.

## ■ TEST CIRCUITS AND WAVEFORMS

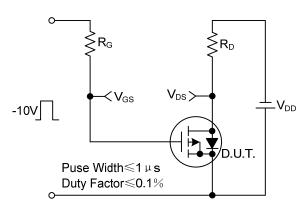
# Gate Charge Test Circuit



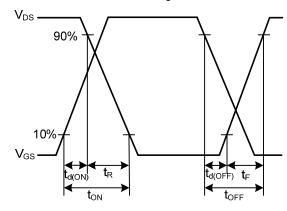
Gate Charge Waveforms



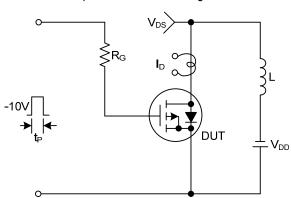
Resistive Switching Test Circuit



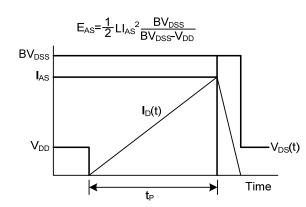
Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms



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